

FORM PTO-1449	APPLICATION NO. 10/782,262	CASE NO. 10541-1932
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Concurrent herewith	ART UNIT 3683
APPLICANT(S): Xubin Song et al.		

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
TJW	2003/0075881 A1	04/24/03	Detorenzis et al.	—	10/23/01
TJW	4,872,702	10/10/89	Medley	—	08/23/88
TJW	5,029,328	07/02/91	Kamimura et al.	—	10/24/89
TJW	5,033,770	07/23/91	Kamimura et al.	—	09/22/89
TJW	5,071,158	12/10/91	Yonekawa et al.	—	08/16/90
TJW	5,043,893	08/27/91	Aburaya et al.	—	12/29/89
TJW	5,103,396	04/07/92	Hiwatashi et al.	—	05/04/90
TJW	5,103,397	04/07/92	Ikemoto et al.	—	04/06/90
TJW	5,104,143	04/14/92	Yonekawa	—	09/21/90
TJW	5,113,345	05/12/92	Mine et al.	—	05/22/90
TJW	5,119,297	06/02/92	Buma et al.	—	02/26/90
TJW	5,144,559	09/01/92	Kamimura et al.	—	06/18/90
TJW	5,162,995	11/10/92	Ikemoto et al.	—	04/06/90
TJW	5,177,681	01/05/93	Sato	—	02/26/91
TJW	5,598,337	01/28/97	Butsuen et al.	—	06/28/95
TJW	5,619,413	04/08/97	Oakley	—	07/08/93
TJW	5,684,698	11/04/97	Fujii et al.	—	04/13/95
TJW	6,032,090	02/29/00	von Bose	—	05/06/97
TJW	6,202,010	03/13/01	Shono et al.	—	10/05/98
TJW	6,259,982	07/10/01	Williams et al.	701/38	02/02/93
TJW	6,282,470	08/28/01	Shono et al.	—	10/05/98
TJW	6,389,341	05/14/02	Davis	—	01/12/01
TJW	6,418,363	07/09/02	Cochofel et al.	—	12/29/00
TJW	6,470,248	10/22/02	Shank et al.	—	11/30/01
TJW	6,598,885	07/29/03	Delorenzis et al.	—	10/23/01

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES NO

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER Thomas Williams	DATE CONSIDERED 1/05/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.